VUE 400-P
SCANNING ACOUSTIC MICROSCOPE

Semiconductor Package Failure Analysis
voids · disbonds · cracks · delamination · internal defects

Customer Interface
Dual 22" HD LED Monitors

Fixtures
Tray Fixture

Instrumentation
Digital Pulser Receiver
Ultrasonic Digitizer (Max 12 GHz)

User Experience Elements
Dual JEDEC Trays
HD LED Lighting
ESD or Stainless Steel Tank

Maintenance Free Scan Axis
Motor:	Quad Linear Servo
Max Velocity:	1500 mm/s
Accuracy & Repeatability:	+/- 0.5 micron

Scan Envelope: 380 mm

Low Maintenance Step Axis:
Step Envelope 350 mm

Low Maintenance Focus Axis:
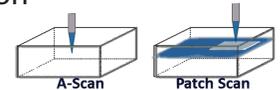Focus Envelope 50 mm

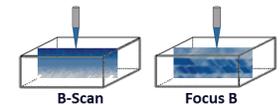### Dimensions:
0.9 m x 0.86 m x 1.18 m (W/D/H)
227 kg

A-Scan · Patch Scan · B-Scan · Focus B · C-Scan · Dual Gate · TX-Scan · Concurrent PE/TX · Top Scan · Counterfeit Detection · Sub B · Cross B · SALI · SALI Groups · D-Scan · 3D
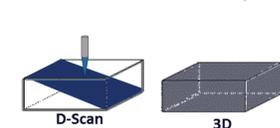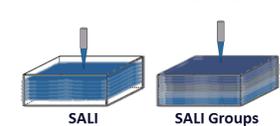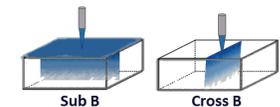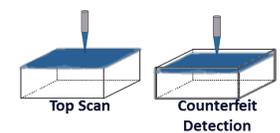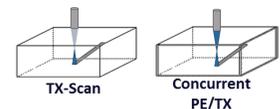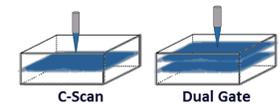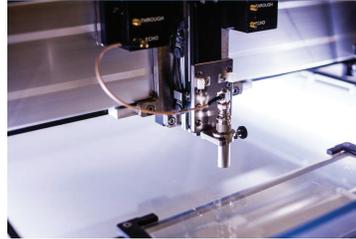
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SCANNING ACOUSTIC MICROSCOPE

Included Software Modes:

- Basic (user friendly)
- Advanced (detailed analysis)
- Production (automated scanning)
- Off-line Analysis (virtual scanning)

OKOS Digital Imaging System (ODIS)

VUE 400-P imaging power surpasses modern standards delivering premium FA Lab features to semiconductor fabrication facilities. ODIS is the latest Acoustic Microscopy software with rich technical content built on current platforms and industry feedback. It includes both time domain and frequency domain imaging in real-time. Advanced analysis is provided through quantitative tools for measurement and classification of parts.

The Analysis version of ODIS allows non-scanning computers to virtually scan, view, and analyze data for simultaneous real-time analysis or post collection review. Supplied with your choice of Windows 7 or 10.

- Counterfeit Detection
- Product Reliability
- Process Validation
- Vendor Qualification
- Product Inspection
- Quality Control
- Failure Analysis
- R&D

Application Specific Transducers
for the highest quality resolution.
Multiple transducer design for enhanced scan capability.

3D Imaging
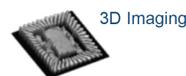
Void Gating (real-time)

C-scan with Multi-gate SALI & SALI Groups

Cluster Analysis (post processing)

Frequency Domain Imaging (FFT)

Threshold Mapping (post processing)

Advanced Time-of-Flight & Thickness Measurements

B-scan & SLICE

Real-time A-scan & A-scan Capture